

# THOR100-X4

# Thermal & Function TEST REPORT

Product	System	System
Manager	Leader	Engineer
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Date: 12/08/2021

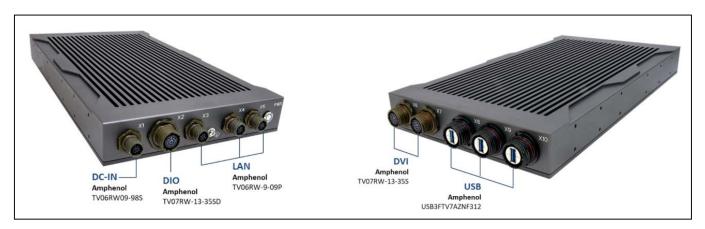
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## 1. SYSTEM SPEC

#### 1-1. PRODUCT PHOTOS



#### 1-2. SYSTEM COFIGURATION

System Configuration		
Motherboard	Perfectron OXY5741A	
CPU	Intel® XEON-E-2276ML	
Memory	Innodisk DDR4-2400 16G SODIMM	
M.2 NVME PCIe SSD	7Starlake M.2 NVME 480GB	
X1~X2	Intel I210 with 10/100/1000Mbp	
Х3	Intel I219LM with 10/100/1000Mbp	
X4	8Bit DIO / Line-out / MIC-in	
X5	DC-IN 18~36V	
X6~X8	USB3.0 TYPE A	
X9~X10	DVI-D	

## 2. Test Plan

#### 2-1. Thermal Measurement Process

Test Purpose	The purpose of performing thermal profile test is to identify potential thermal problem of the EUT. And it is to aid products in reliability assessment considering that semiconductor failure rates rise rapidly with increasing junction temperature In case of systems cooling, patterns will vary with stacking choices, temperature/thermal mapping can aid in the development of optimum tacking arrangements		
Test Equipment	1. KSON THS-B4T-150 Chamber 2. YOKOGAWA MV1000, Thermometer (FLUKE50D K/J)		
Quantity Tested	Minimum 1 Set		
Test Software	Passmark Burn-In Test under Windows 10		
Test Procecedure	<ol> <li>Thermal pre-scan measurement:         Temperature: -40~70°C /60%RH</li> <li>Thermal actual measurement:         a. Select the test points according to the IR photo and attach thermocouples to the hot points         b. Put the EUT in thermal chamber and set the temperature profile of as test             specification         c. Turn on the thermal chamber and power on the EUT to enter windows environment to run Max         Power Test + 3DMARK 2003 application program             d. After the EUT executing the test software for 4 hours, record thermal maximum value for each             thermocouples point.             e. Turn off the thermal chamber and EUT             f. Verify and check recorded figure of each components to its' operating temperature             range listed in specification/approval sheet of each measured component</li> </ol>		
Test diagram of curves	Temp 70 (°C)  1.5 3 4.5 5 6.5 8 9.5 10 11.5 12 13.5 14 15.5 16		

# 2-2. THOR100-X4 TEST RESULT

#### **TEST ITEM:**

#### 2.2.1 TEMPERATURE CYCLE

# Burn-in test under each temperature with maximum quantity of external devices on all I/O connected and full loading status on each device

Test Temperature	Test Result
-40°C	PASS
0℃	PASS
25℃	PASS
<b>40</b> ℃	PASS
<b>50</b> °C	PASS
60℃	PASS
<b>70</b> ℃	PASS

#### 2.2.2 I/O FUNCTION

#Confirm the system specifications and I/O connection to ensure that they are functioning properly

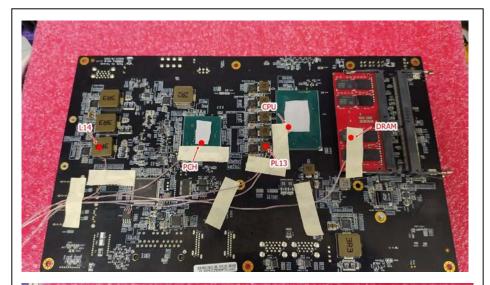
Item	Criteria	
	Connection 2.5" USB3.0 SSD device and transfer data test	
USB3.0 *3	PassMark USB3.0 Loopback Plugs for Troubleshooting and	
	Testing USB 3.0 ports.	
LAN * 3	Connection 2.5" USB3.0 SSD device and transfer data test	<b>PASS</b>
DVI-D *2	Check work well	PASS
Line Out/Mic In	Check work well	PASS

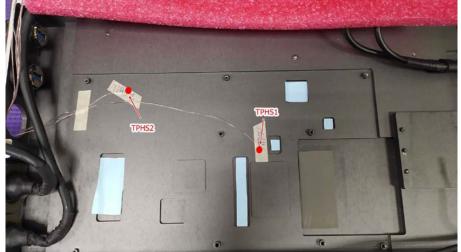
#### 2.2.3 LOW-TEMP. BOOT-UP

#Power supply under  $-40^{\circ}$ C and ensure that the system boot up properly

Ambient Temp.	Test Result
-40°C	PASS

# 3. Thermal Test Point







TEST POINT NO.	Test Point	
1	CPU	
2	PCH	
3	DRAM	
4	L14	
5	PL13	
6	TPHS1	
7	TPHS2	
8	SK708 HS	
9	TDK FILTER	
10	M.2 NVME SSD	

## 4. Test Photo in LAB

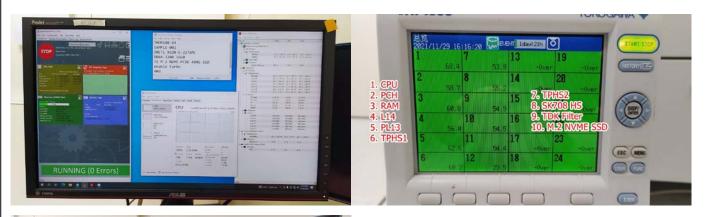
#### - Chamber in 25℃





TEST POINT NO.	Ambient Tem; Test Point	25℃
	CPU FRQ.	2.4G
	CPU Tj. (<105℃)	65
1	CPU	45.6
2	РСН	36.2
3	DRAM	38.4
4	L14	33.6
5	PL13	40.2
6	TPHS1	37.9
7	TPHS2	32.4
8	SK708	33.2
9	TDK FILTER	32.5
10	M.2 NVME SSD	32.5

#### - Chamber in 40℃





TEST POINT NO.	Ambient Tem Test Point	40 <b>℃</b>
	CPU FRQ.	2.25G
	CPU Tj. (<105℃)	84
1	CPU	68.4
2	PCH	58.7
3	DRAM	60.8
4	L14	56
5	PL13	62.6
6	TPHS1	60.2
7	TPHS2	53.9
8	SK708	55.2
9	TDK FILTER	54.9
10	M.2 NVME SSD	54.5

#### - Chamber in 50℃





TEST POINT NO.	Ambient Tem Test Point	50 <b>℃</b>
	CPU FRQ.	2.5G
	CPU Tj. (<105℃)	95
1	CPU	78.9
2	РСН	69.2
3	DRAM	71.7
4	L14	66.4
5	PL13	73.2
6	TPHS1	70.6
7	TPHS2	64.3
8	SK708	65.4
9	TDK FILTER	65.4
10	M.2 NVME SSD	65

#### - Chamber in 60℃





TEST POINT NO.	Ambient Tem Test Point	60 <b>°C</b>
	CPU FRQ.	1.93G
	CPU Tj. (<105℃)	100
1	CPU	87.1
2	РСН	78.4
3	DRAM	80.7
4	L14	76
5	PL13	82
6	TPHS1	79.6
7	TPHS2	73.8
8	SK708	752
9	TDK FILTER	74.6
10	M.2 NVME SSD	75.2

#### - Chamber in 70℃





TEST POINT NO.	Ambient Tem Test Point	70 <b>°C</b>
	CPU FRQ.	1.48G
	CPU Tj. (<105℃)	100
1	CPU	92.6
2	РСН	85.5
3	DRAM	87.5
4	L14	83.6
5	PL13	87.5
6	TPHS1	86.3
7	TPHS2	81.5
8	SK708	82.7
9	TDK FILTER	82.1
10	M.2 NVME SSD	82.6

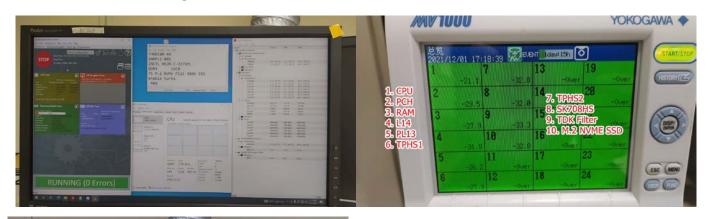
#### - Chamber in 0°C





TEST POINT NO.	Ambient Tem:	0°C		
	CPU FRQ.	2.4G		
	CPU Tj. (<105℃)	38		
1	CPU	19.9		
2	РСН	11		
3	DRAM	13		
4	L14	8.5		
5	PL13	14.7		
6	TPHS1	12.5		
7	TPHS2	7.5		
8	SK708	8.2		
9	TDK FILTER	7.3		
10	M.2 NVME SSD	7.4		

#### - Chamber in -40℃





TEST POINT NO.	Ambient Tem; Test Point	-40℃	
	CPU FRQ.	2.4G	
	CPU Tj. (<105℃)	0	
1	CPU	-21.1	
2	РСН	-29.5	
3	DRAM	-27.9	
4	L14	-31.8	
5	PL13	-26.2	
6	TPHS1	-27.9	
7	TPHS2	-32.8	
8	SK708	-32	
9	TDK FILTER	-33.3	
10	M.2 NVME SSD	-32.8	

#### Low Temperature SYSTEM Boot up Test

- Ambient Temp. -40℃





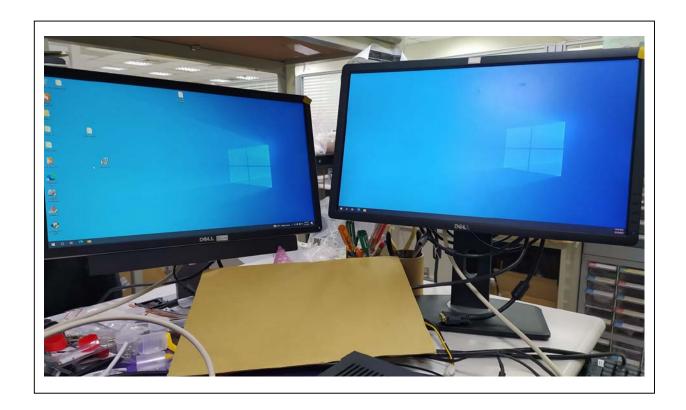


# 5. THOR100-X4 THERMAL TEST RESULT (-40~+70 DEGREE)

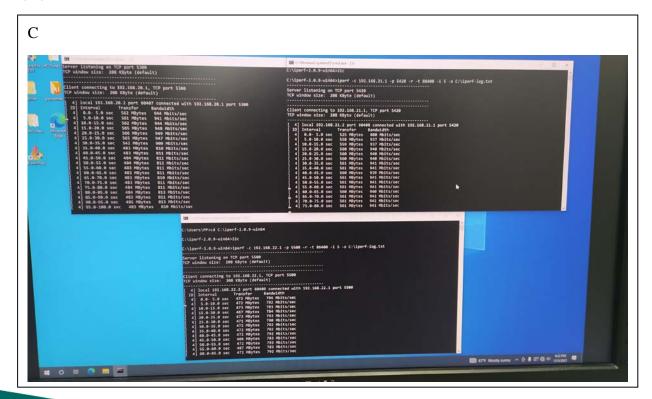
TEST POINT NO.	Ambient Tem	-40℃	0°C	25°C	40℃	50 <b>°</b> C	60°C	70°C
	CPU FRQ.	2.4G	2.4G	2.4G	2.25G	2.5G	1.93G	1.48G
	CPU Tj. (<105℃)	0	38	65	84	95	100	100
1	CPU	-21.1	19.9	45.6	68.4	78.9	87.1	92.6
2	РСН	-29.5	11	36.2	58.7	69.2	78.4	85.5
3	DRAM	-27.9	13	38.4	60.8	71.7	80.7	87.5
4	L14	-31.8	8.5	33.6	56	66.4	76	83.6
5	PL13	-26.2	14.7	40.2	62.6	73.2	82	87.5
6	TPHS1	-27.9	12.5	37.9	60.2	70.6	79.6	86.3
7	TPHS2	-32.8	7.5	32.4	53.9	64.3	73.8	81.5
8	SK708	-32	8.2	33.2	55.2	65.4	752	82.7
9	TDK FILTER	-33.3	7.3	32.5	54.9	65.4	74.6	82.1
10	M.2 NVME SSD	-32.8	7.4	32.5	54.5	65	75.2	82.6

### 6. I/O FUNCTION TEST

#### (1) DVI OUTPUT TEST



#### (2) LAN transfer data test



#### (3) USB 3.0 transfer data test

